



TK4A60D

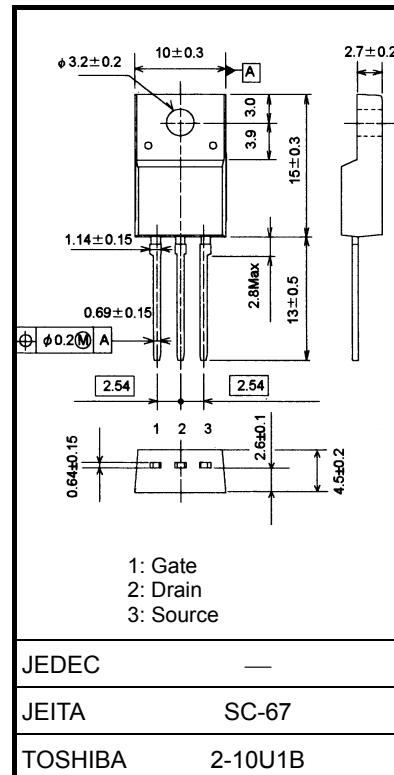
Switching Regulator Applications

Unit: mm

- Low drain-source ON-resistance: $R_{DS(ON)} = 1.4 \Omega$ (typ.)
- High forward transfer admittance: $|Y_{fs}| = 2.5 \text{ S}$ (typ.)
- Low leakage current: $I_{DSS} = 10 \mu\text{A}$ (max) ($V_{DS} = 600 \text{ V}$)
- Enhancement mode: $V_{th} = 2.4$ to 4.4 V ($V_{DS} = 10 \text{ V}$, $I_D = 1 \text{ mA}$)

Absolute Maximum Ratings ($T_a = 25^\circ\text{C}$)

Characteristics		Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	600	V
Gate-source voltage		V_{GSS}	± 30	V
Drain current	DC (Note 1)	I_D	4	A
	Pulse ($t = 1 \text{ ms}$) (Note 1)	I_{DP}	16	
Drain power dissipation ($T_c = 25^\circ\text{C}$)		P_D	35	W
Single pulse avalanche energy (Note 2)		E_{AS}	187	mJ
Avalanche current		I_{AR}	4	A
Repetitive avalanche energy (Note 3)		E_{AR}	3.5	mJ
Channel temperature		T_{ch}	150	$^\circ\text{C}$
Storage temperature range		T_{stg}	-55 to 150	$^\circ\text{C}$



Weight : 1.7 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/"Derating Concept and Methods") and individual reliability data (i.e. reliability test report and estimated failure rate, etc.).

Thermal Characteristics

Internal Connection

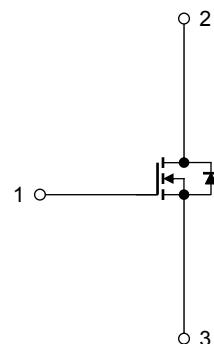
Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	$R_{th}(\text{ch-c})$	3.57	$^\circ\text{C/W}$
Thermal resistance, channel to ambient	$R_{th}(\text{ch-a})$	62.5	$^\circ\text{C/W}$

Note 1: Ensure that the channel temperature does not exceed 150°C .

Note 2: $V_{DD} = 90 \text{ V}$, $T_{ch} = 25^\circ\text{C}$ (initial), $L = 20.5 \text{ mH}$, $R_G = 25 \Omega$, $I_{AR} = 4 \text{ A}$

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device. Handle with care.



Electrical Characteristics ($T_a = 25^\circ C$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Gate leakage current	I_{GSS}	$V_{GS} = \pm 30 V, V_{DS} = 0 V$	—	—	± 1	μA
Drain cut-off current	I_{DSS}	$V_{DS} = 600 V, V_{GS} = 0 V$	—	—	10	μA
Drain-source breakdown voltage	$V_{(BR) DSS}$	$I_D = 10 mA, V_{GS} = 0 V$	600	—	—	V
Gate threshold voltage	V_{th}	$V_{DS} = 10 V, I_D = 1 mA$	2.4	—	4.4	V
Drain-source ON-resistance	$R_{DS (\text{ON})}$	$V_{GS} = 10 V, I_D = 2 A$	—	1.4	1.7	Ω
Forward transfer admittance	$ Y_{fs} $	$V_{DS} = 10 V, I_D = 2 A$	0.7	2.5	—	S
Input capacitance	C_{iss}	$V_{DS} = 25 V, V_{GS} = 0 V, f = 1 \text{ MHz}$	—	600	—	pF
Reverse transfer capacitance	C_{rss}		—	4	—	
Output capacitance	C_{oss}		—	70	—	
Switching time	Rise time	t_r	 Duty $\leq 1\%$, $t_W = 10 \mu s$	—	18	—
	Turn-on time	t_{on}		—	40	—
	Fall time	t_f		—	8	—
	Turn-off time	t_{off}		—	55	—
Total gate charge	Q_g	$V_{DD} \approx 400 V, V_{GS} = 10 V, I_D = 4 A$	—	12	—	nC
Gate-source charge	Q_{gs}		—	7	—	
Gate-drain charge	Q_{gd}		—	5	—	

Source-Drain Ratings and Characteristics ($T_a = 25^\circ C$)

Characteristics	Symbol	Test Condition	Min	Typ.	Max	Unit
Continuous drain reverse current (Note 1)	I_{DR}	—	—	—	4	A
Pulse drain reverse current (Note 1)	I_{DRP}	—	—	—	16	A
Forward voltage (diode)	V_{DSF}	$I_{DR} = 4 A, V_{GS} = 0 V$	—	—	-1.7	V
Reverse recovery time	t_{rr}	$I_{DR} = 4 A, V_{GS} = 0 V,$ $dI_{DR}/dt = 100 A/\mu s$	—	1200	—	ns
Reverse recovery charge	Q_{rr}		—	7	—	μC

Marking